BS EN IEC 61280-4-1:2019 Incorporating corrigendum April 2020



BSI Standards Publication

Fibre-optic communication subsystem test procedures

Part 4-1: Installed cabling plant — Multimode attenuation measurement



National foreword

This British Standard is the UK implementation of EN IEC 61280-4-1:2019. It is identical to IEC 61280-4-1:2019, incorporating corrigendum April 2020. It supersedes BS EN 61280-4-1:2009, which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee GEL/86/3, Fibre optic systems and active devices.

A list of organizations represented on this committee can be obtained on request to its secretary.

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European foreword

The text of document 86C/1575/FDIS, future edition 3 of IEC 61280-4-1, prepared by SC 86C "Fibre optic systems and active devices" of IEC/TC 86 "Fibre optics" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61280-4-1:2019.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2020-03-26 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2022-06-26 document have to be withdrawn

This document supersedes EN 61280-4-1:2009 and all of its amendments and corrigenda (if any)

This edition constitutes a technical revision including the following significant technical changes with respect to the previous edition:

a) changes to Annex F on encircled flux to harmonise with IEC TR 62614-2, but keeping the encircled flux limits defined in Tables F.2 to F.5 unchanged;

- b) addition of an equipment cord method in Annex D;
- c) inclusion of testing bend insensitive multimode optical fibre;
- d) updates to measurement uncertainty;
- e) definition of additional cabling configurations;
- f) changes to Table 5 on spectral requirements.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

Endorsement notice

The text of the International Standard IEC 61280-4-1:2019 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60793-1-40	NOTE	Harmonized as EN IEC 60793-1-40
IEC 60793-2	NOTE	Harmonized as EN 60793-2
IEC 60793-2-10	NOTE	Harmonized as EN 60793-2-10
IEC 60793-2-50	NOTE	Harmonized as EN IEC 60793-2-50
IEC 60794-2-21	NOTE	Harmonized as EN IEC 60794-2-21
IEC 61300-3-6	NOTE	Harmonized as EN 61300-3-6
IEC 61300-3-45	NOTE	Harmonized as EN 61300-3-45
IEC 61745	NOTE	Harmonized as EN 61745
IEC 61755-6-2	NOTE	Harmonized as EN IEC 61755-6-2
IEC 62664-1-1	NOTE	Harmonized as EN 62664-1-1
IEC 62614:2010	NOTE	Harmonized as EN 62614:2010 (not modified)

Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

Publication	Year	<u>Title</u>	<u>EN/HD</u>	Year
IEC 60825-2	-	Safety of laser products - Part 2: Safety of optical fibre communication systems (OFCS)	EN 60825-2	-
IEC 61280-1-3	-	Fibre optic communication subsystem test procedures - Part 1-3: General communication subsystems - Central wavelength and spectral width measurement	EN 61280-1-3	-
IEC 61280-1-4	-	Fibre optic communication subsystem test procedures - Part 1-4: General communication subsystems - Light source encircled flux measurement method	EN 61280-1-4	-
IEC 61300-3-35	-	Fibre optic interconnecting devices and passive components - Basic test and measurement procedures - Part 3-35: Examinations and measurements - Visual inspection of fibre optic connectors and fibre-stub transceivers	EN 61300-3-35	-
IEC 61315	-	Calibration of fibre-optic power meters	EN IEC 61315	-
IEC 61746-2	-	Calibration of optical time-domain reflectometers (OTDR) - Part 2: OTDR for multimode fibres	EN 61746-2	-

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